

Test Compression for Dynamically Reconfigurable Processors

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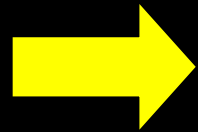
August 31st, 2010

Today's Key Message

2.7

times shorter test time

Outline



- **Background**

- **Our solution: DPC**

- **Evaluation**

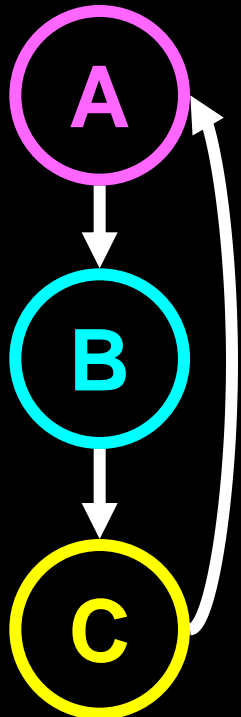
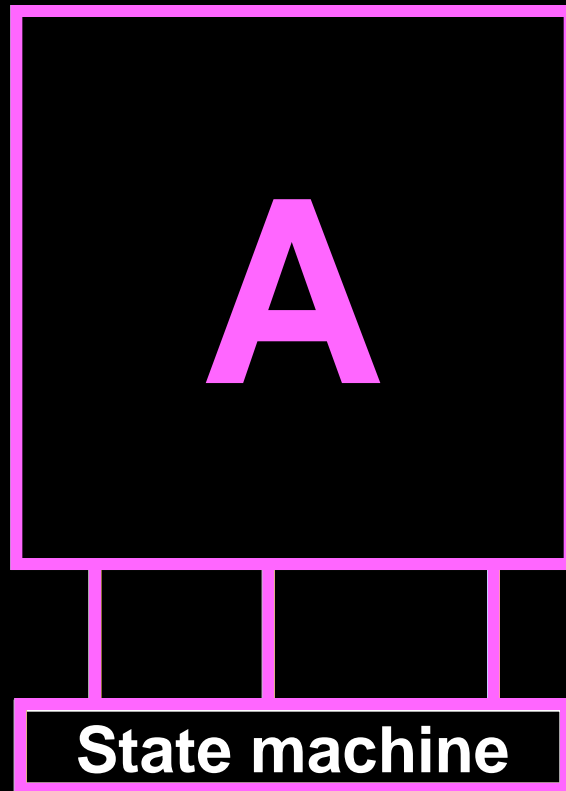
- **Conclusion**

What is DRP?

**Dynamically switching
multiple contexts every cycle**

Program
dataflow

PE array



Benefits:

- Full programmability
- High performance
- Small area occupation

Product examples:

Printers



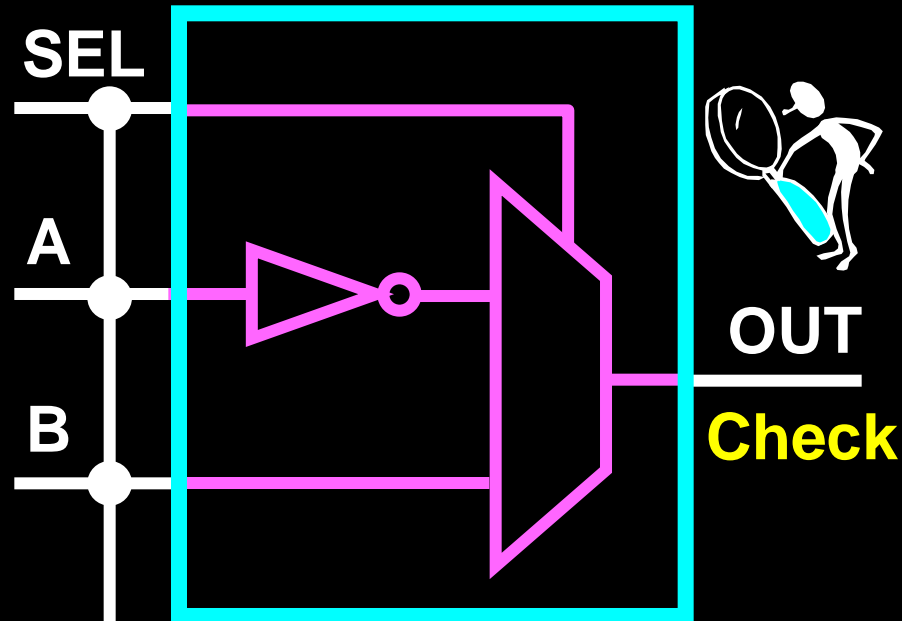
Cameras



Testing Reconfigurable Devices

ASIC:

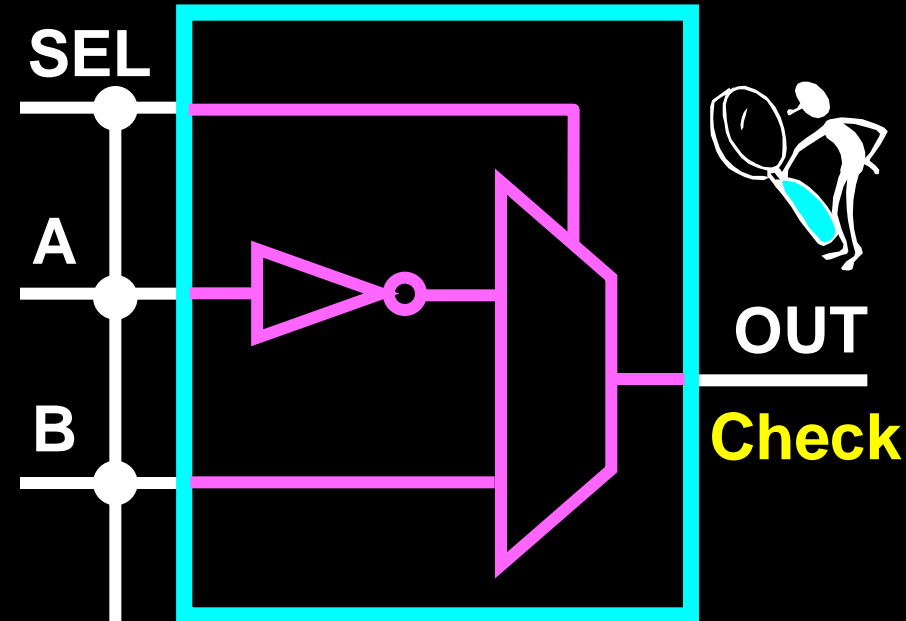
FIXED circuit



Test
vector

FPGA/DRP:

FLEXIBLE circuit

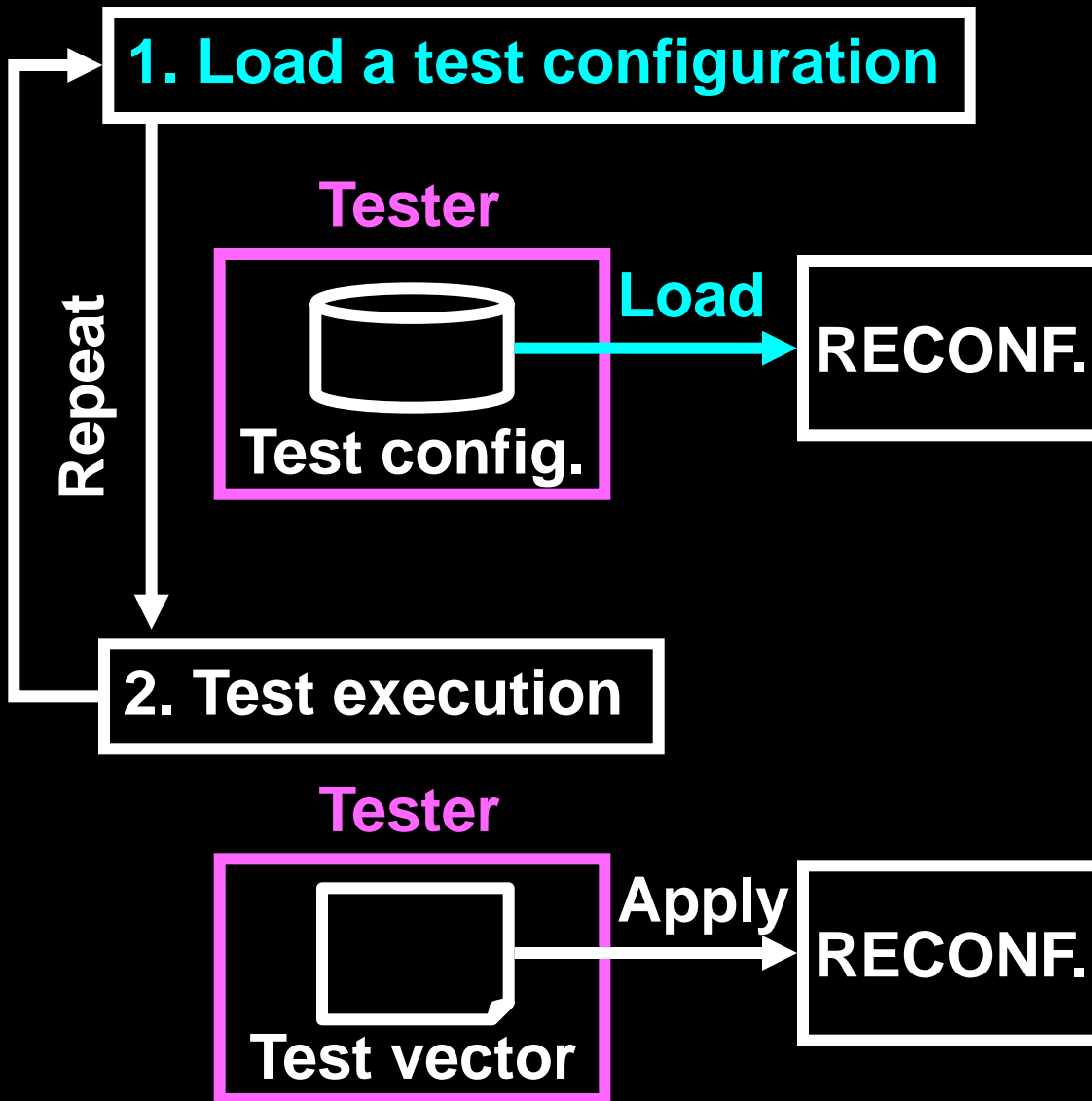


Test
vector

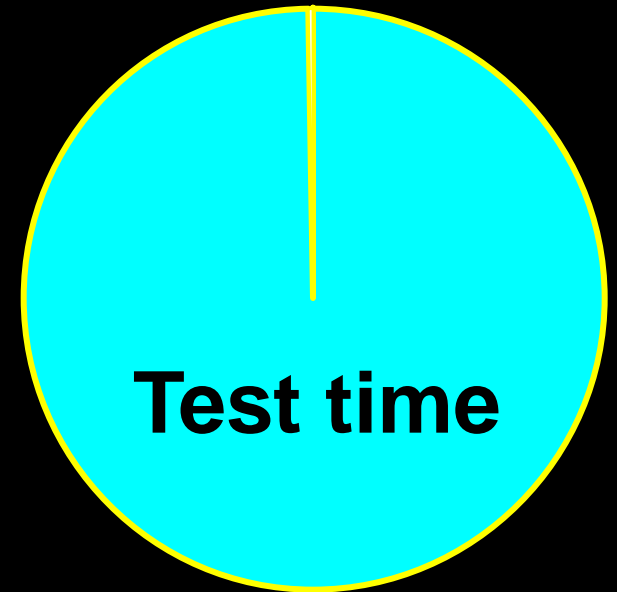


Test
configuration

What is the Problem?



2. Test execution
(1%~)



1. Load
test configurations
(~99%)

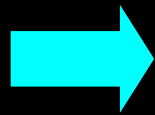
Big problem!

Test Time Reduction Techniques

Already
done

- High clock frequency
- A number of test pins
- Simultaneous testing

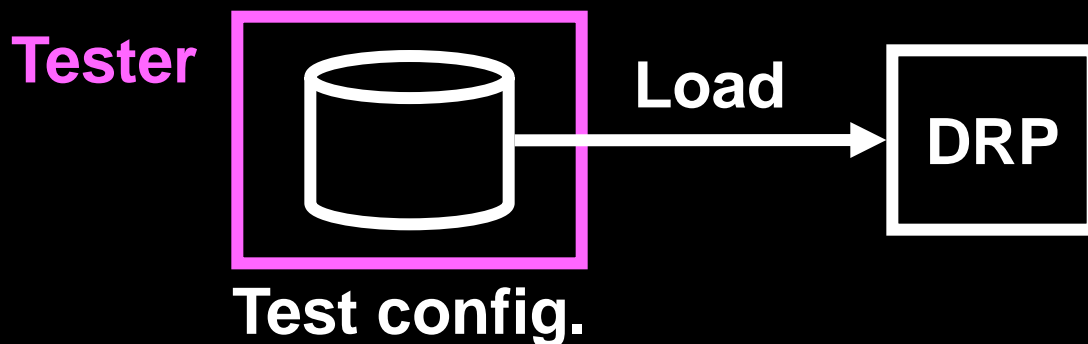
Our
approach



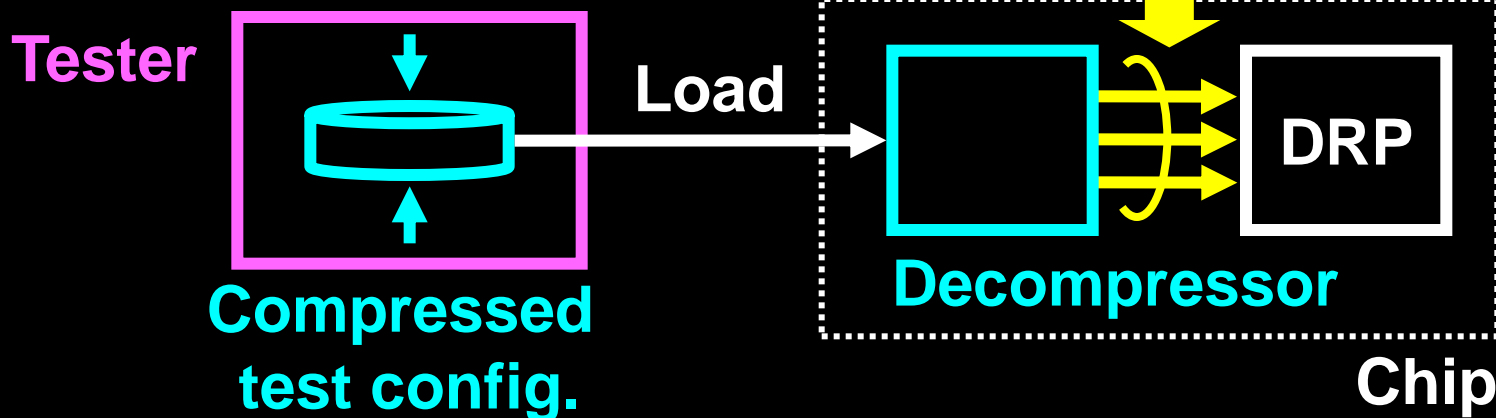
- Test compression

What is Test Compression?

Normal testing



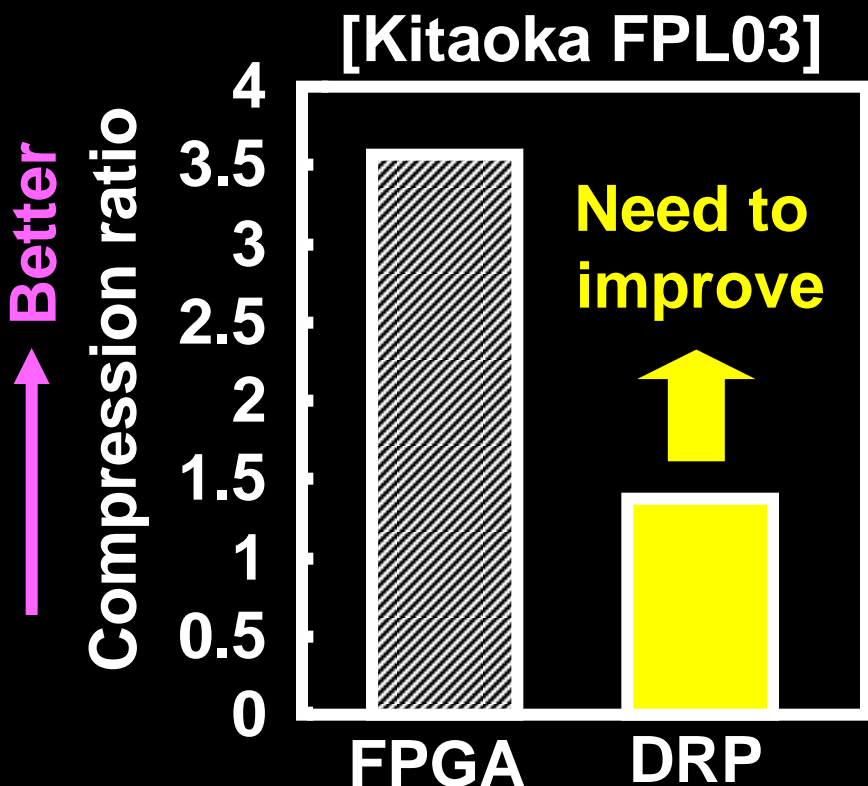
Test compression



Requirements

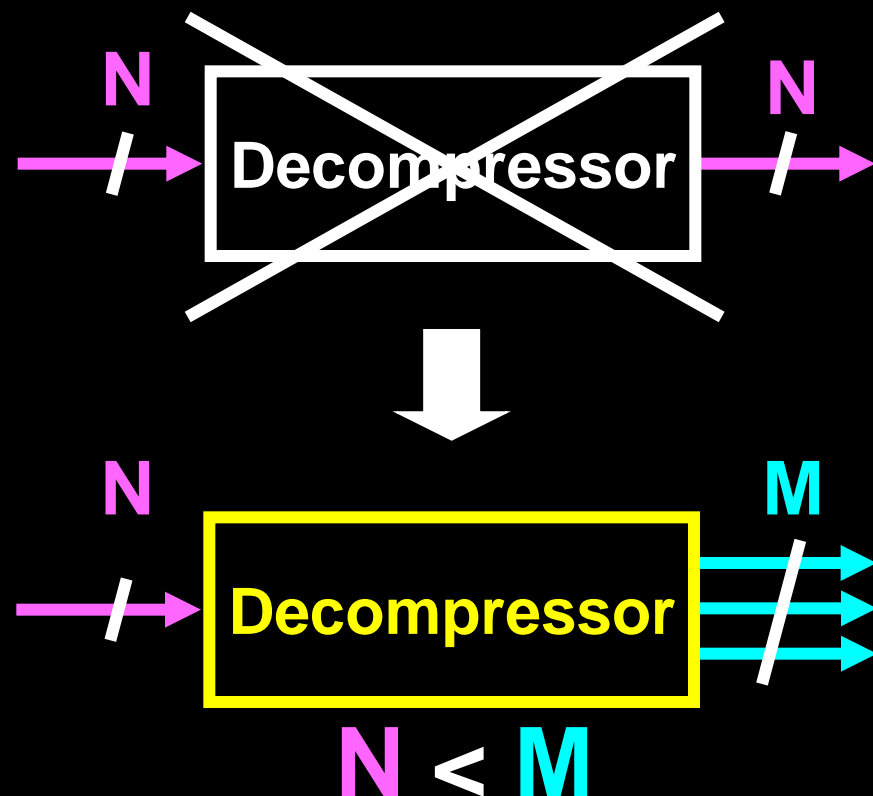
For DRP

High compression ratio



For test

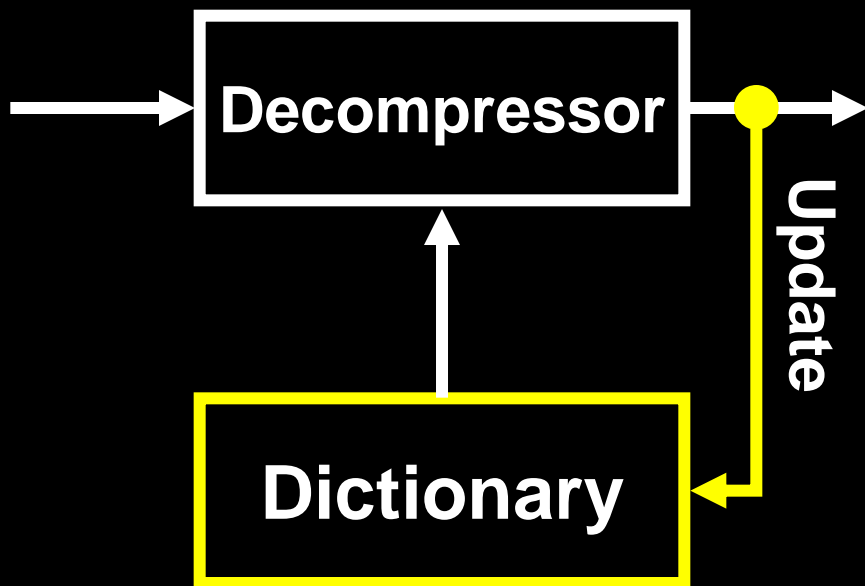
High decompression bandwidth



Conventional Approaches

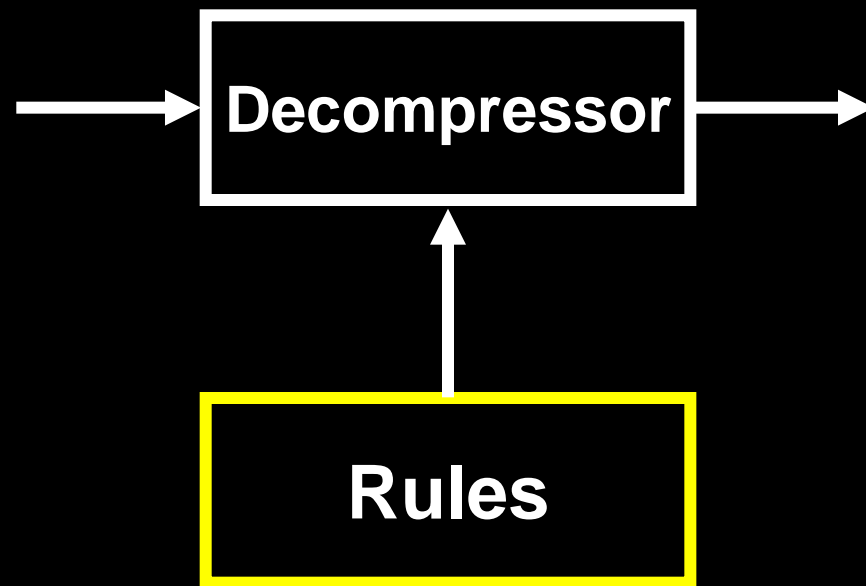
Dictionary-based
(ex. LZ [17])

Use a dictionary
updated by data



Rule-based
(ex. FPC [20])

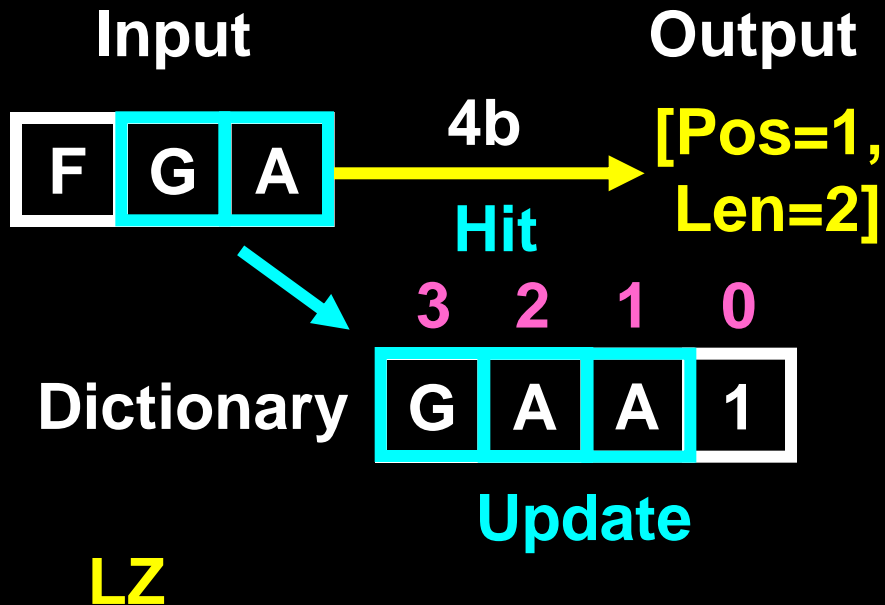
Use pre-defined rules



Dictionary-Based Approach

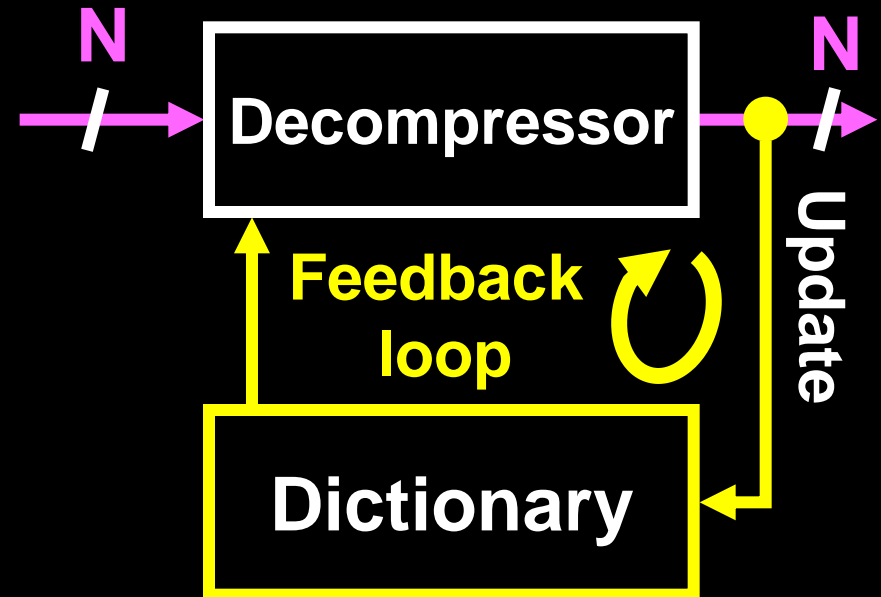
Compression
ratio: **FAIR** 😊

Adaptively match
various symbols



Decompression
bandwidth: **BAD** 😞

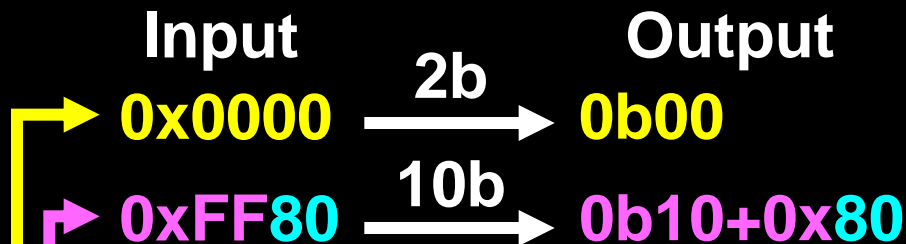
Slow due to
symbol dependence



Rule-Based Approach

Compression
ratio: **BAD** 😞

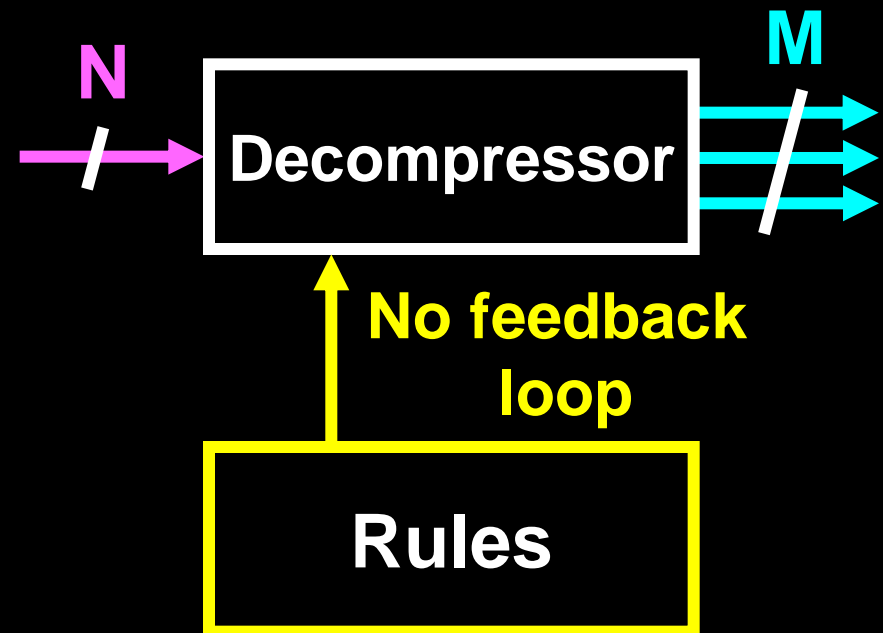
Dependent on
application domains



| 16bit rule | Prefix | Data |
|------------|--------|-------|
| All zero | 0b00 | N/A |
| Sign ext. | 0b01 | 4bit |
| Sign ext. | 0b10 | 8bit |
| Default | 0b11 | 16bit |

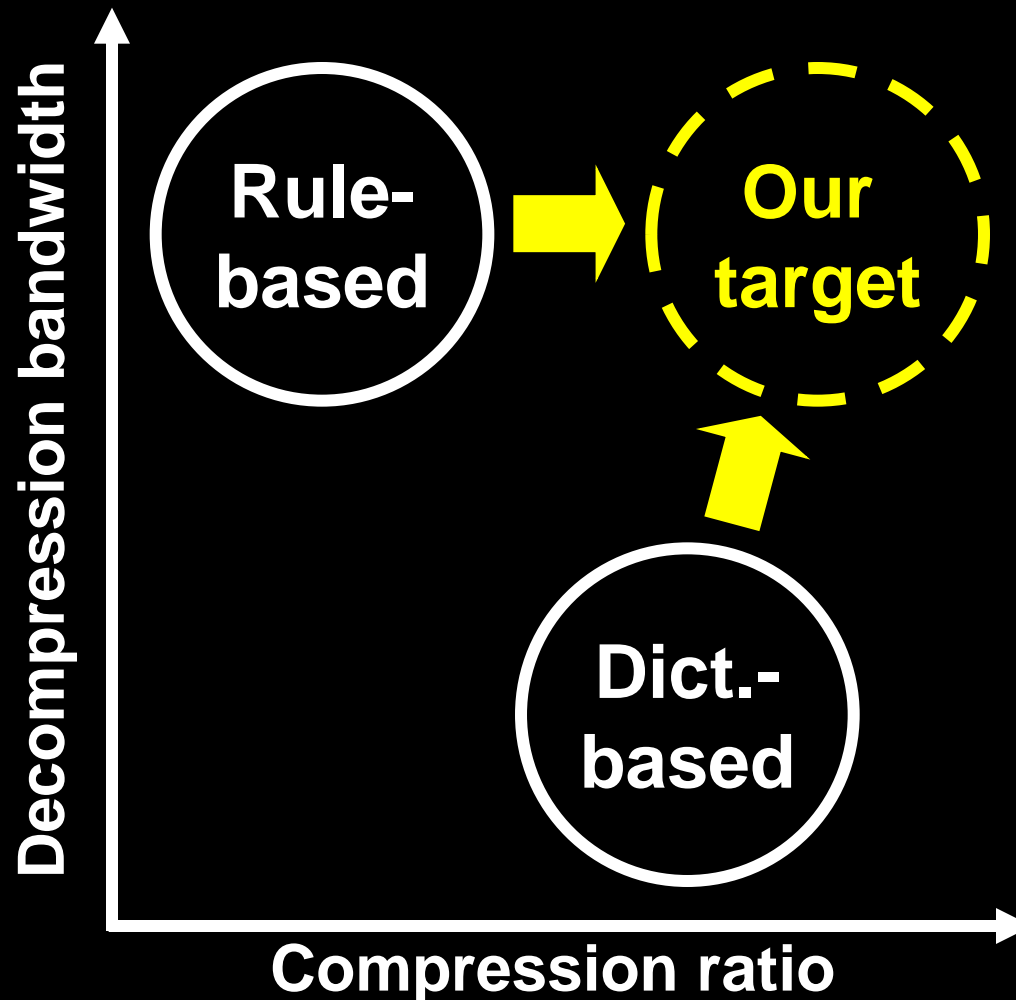
Decompression
bandwidth: **GOOD** 😊

Fast because of
symbol independence



Summary of Background

A new compression approach is required



Outline

✓ • **Background**

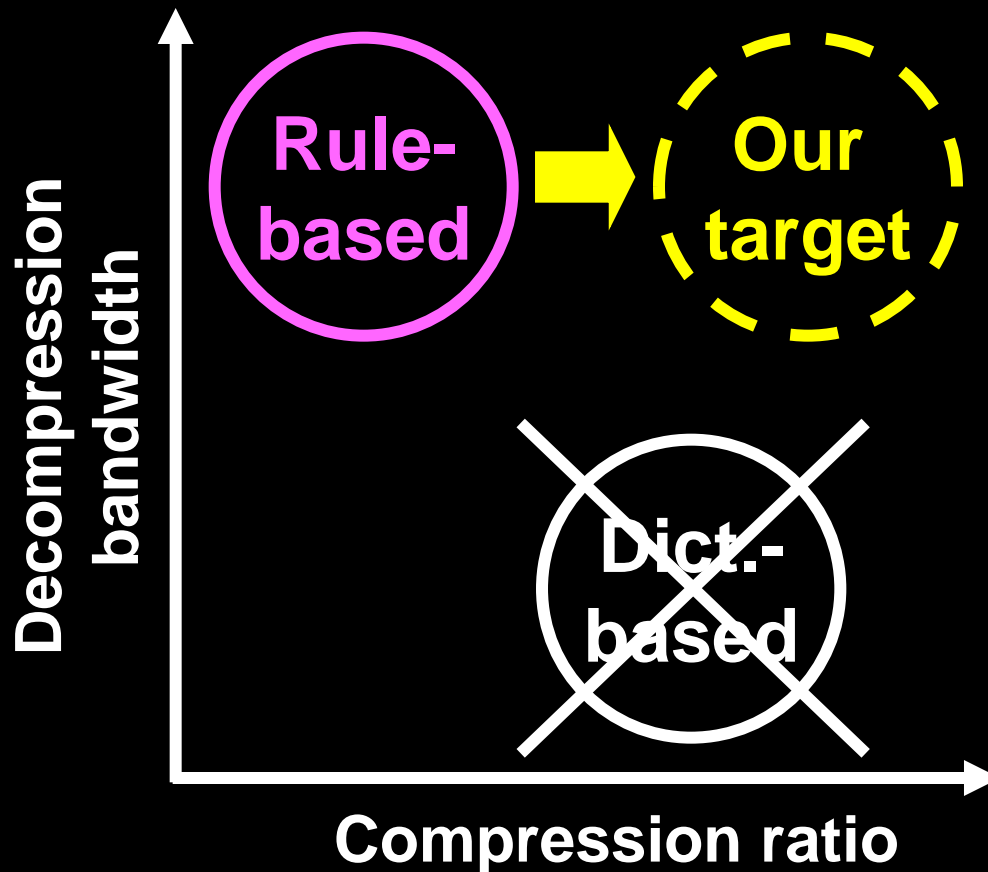
➔ • **Our solution: DPC**

• **Evaluation**

• **Conclusion**

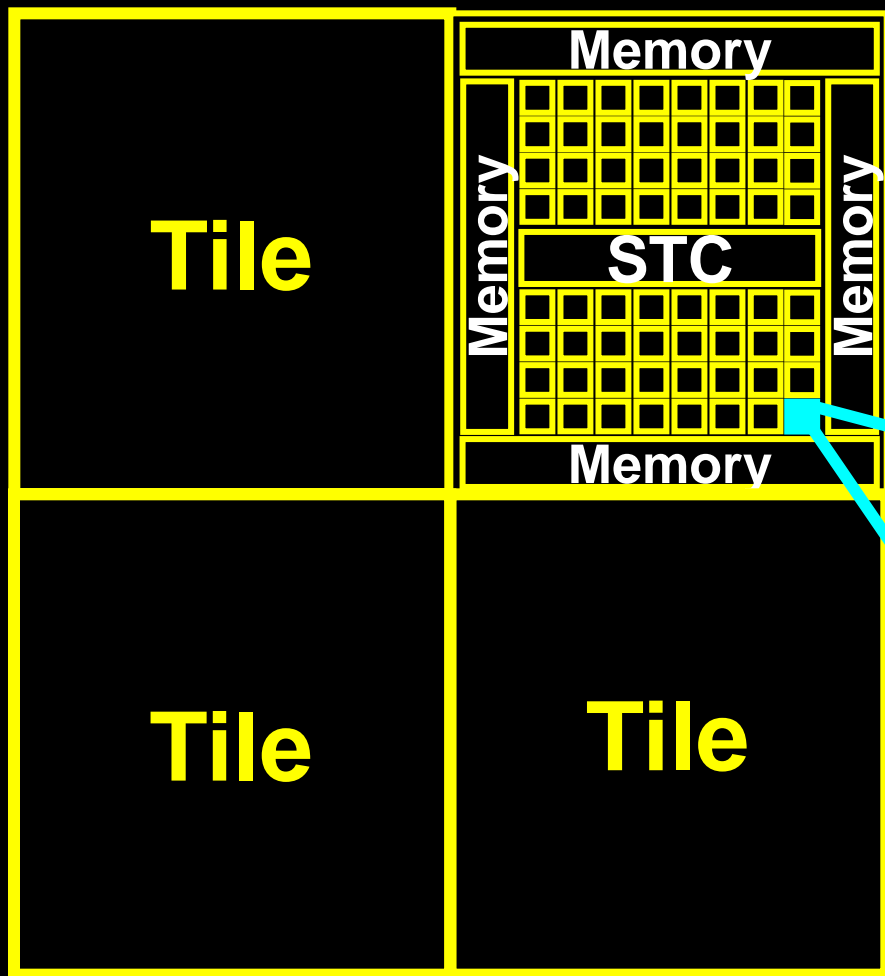
Our Approach

Improving compression ratios,
exploiting the features of test configs.



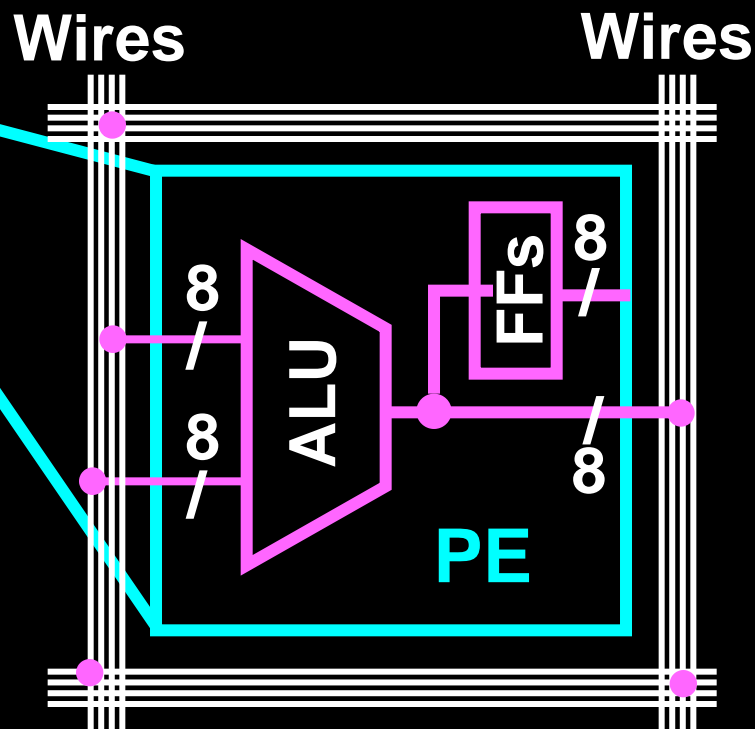
Target Architecture

Tile-based architecture with 8-bit PEs



Per tile

| | |
|-------------|-----|
| # of PEs | 64 |
| # of states | 128 |



STC=State Transition Controller

Test Configurations

DRP: 64-bit, byte-addressing format

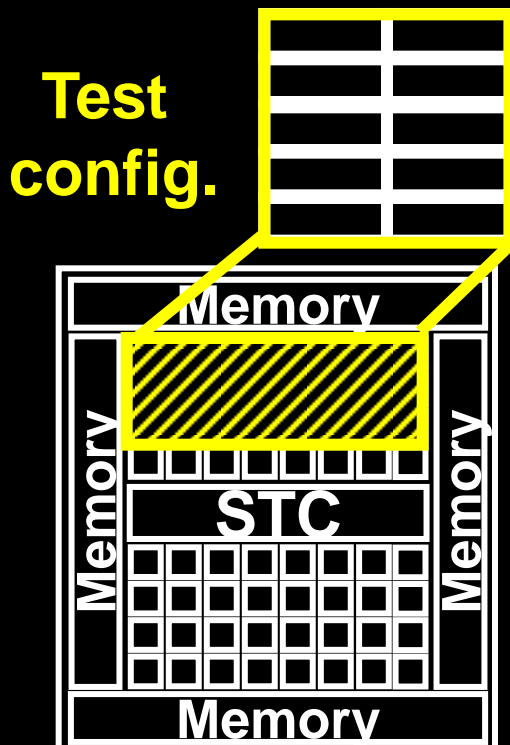
PE positions

PE instructions

Address (32bit)

Data (32bit)

(c.f. FPGA: a bit-stream format)



Address feature:

- High spatial locality
(=Tested PEs are tightly-packed)

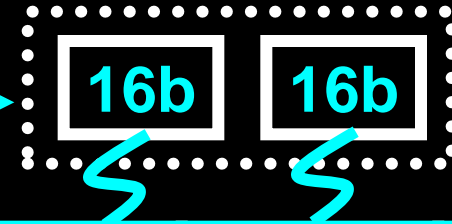
Data feature:

- Fine-grained pattern locality
(=Tested PEs use similar instructions)

Double Pattern Compression

| | |
|----------|-------|
| Address1 | Data1 |
| Address2 | Data2 |

Data split



Address differentiation

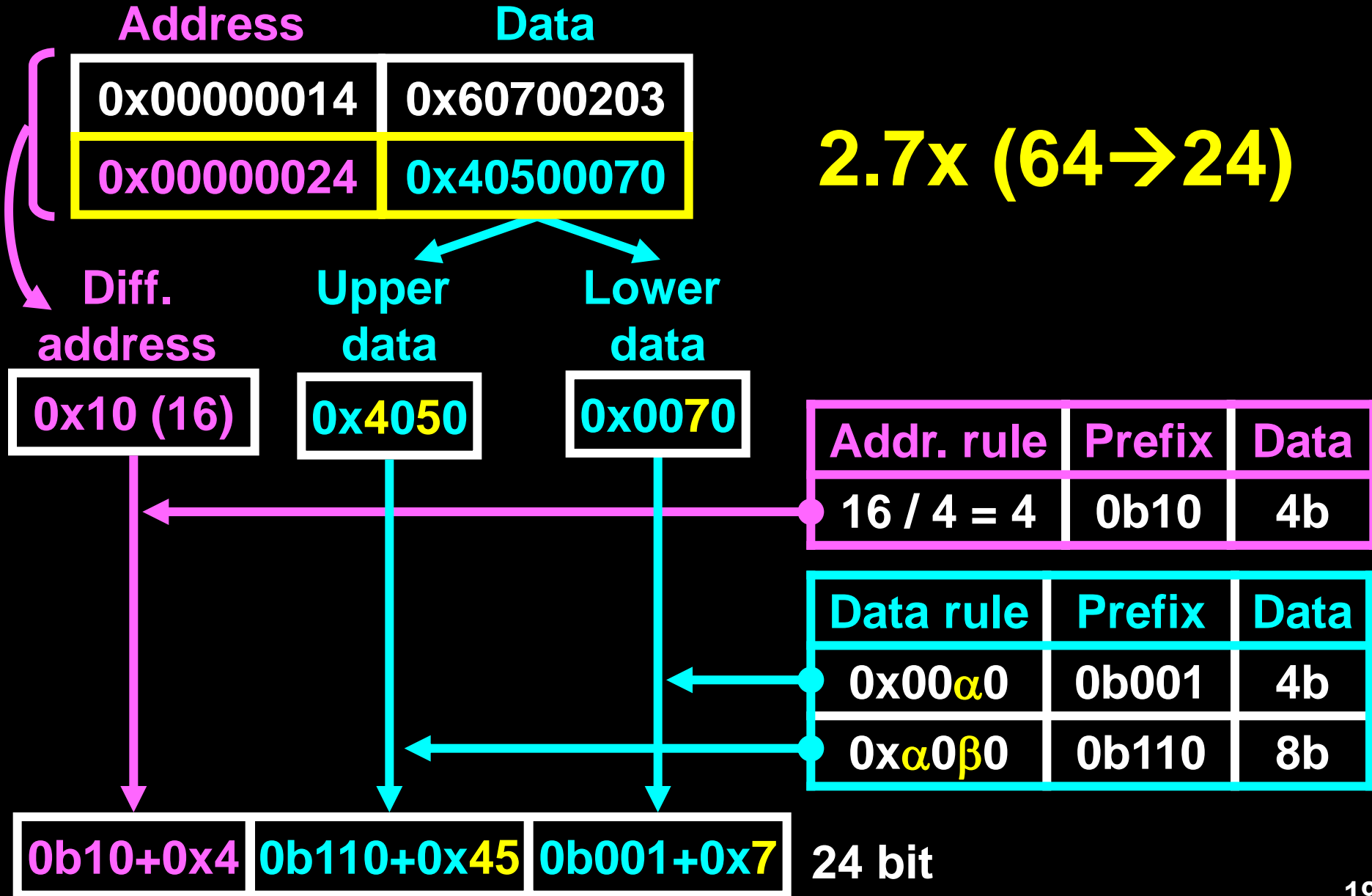
Diff. addr. (= Address2 - Address1)

| Addr. rule | Prefix | Data |
|----------------------|--------|------|
| Address divided by 4 | 0b00 | 1b |
| | 0b01 | 2b |
| | 0b10 | 4b |
| | 0b11 | 30b |

| Data rule | Prefix | Data |
|-----------|--------|------|
| 0x0000 | 0b000 | N/A |
| 0x00α0 | 0b001 | 4b |
| 0x000α | 0b010 | 4b |
| 0x00αβ | 0b011 | 8b |
| 0xαβαβ | 0b100 | 8b |
| 0xαβ00 | 0b101 | 8b |
| 0xα0β0 | 0b110 | 8b |
| Default | 0b111 | 16b |

α, β = any hex. values

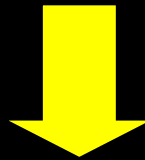
Example



Question

How can we obtain the rules?

- **Patterns**
- **The number of rules**
- **Split data width**

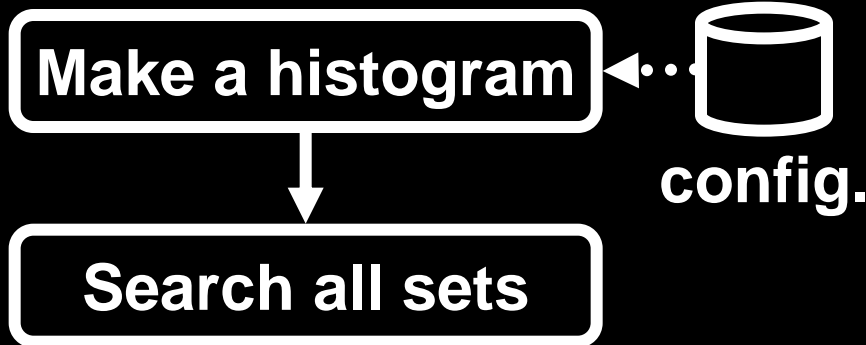


Rule automation

Rule Automation - Algorithms

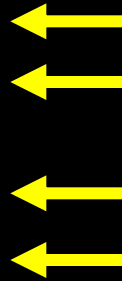
Address rule automation

A few hours



| Diff. addr. | Count |
|-------------|-------|
| 1 bit | 80900 |
| 2 bit | 20050 |
| ... | ... |
| 32 bit | 1021 |

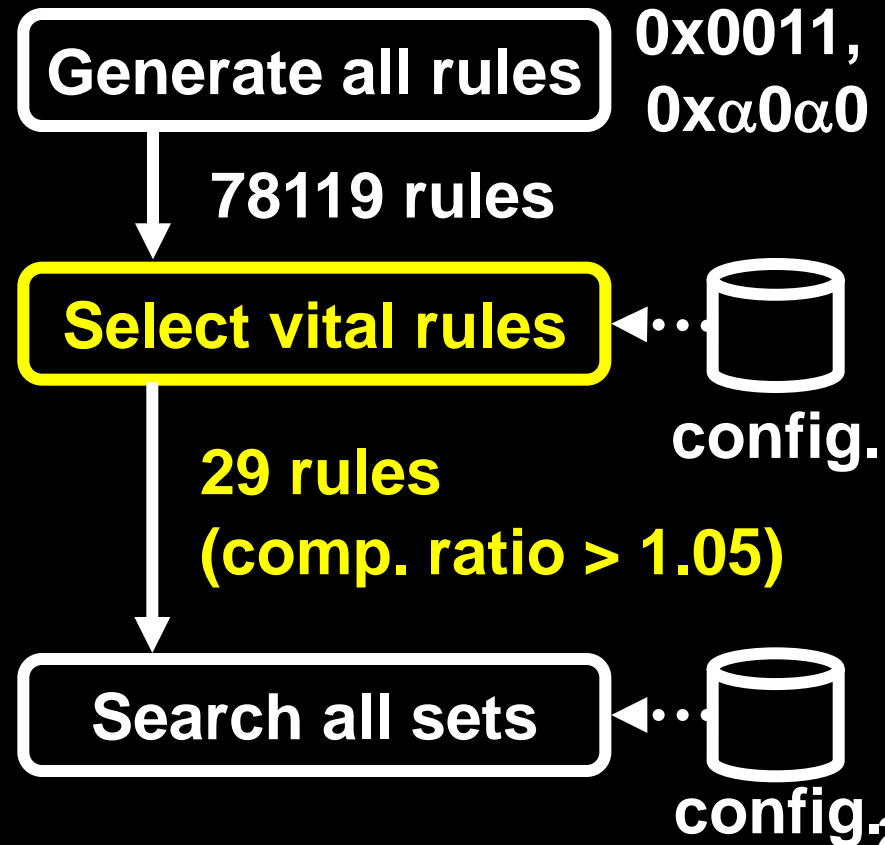
Select



Data rule automation

One day

Ex.: split data width=16b



0x0011,
0xα0α0

config.

config.₂₁

Summary of DPC

Fully-automated, rule-based approach

Requirements:

High
compression
ratio

High
decompression
bandwidth

↓
Exploit
features

↓
Rule-
based

Our approach:

Double pattern compression

↓
Improve
comp. ratio

Technique:

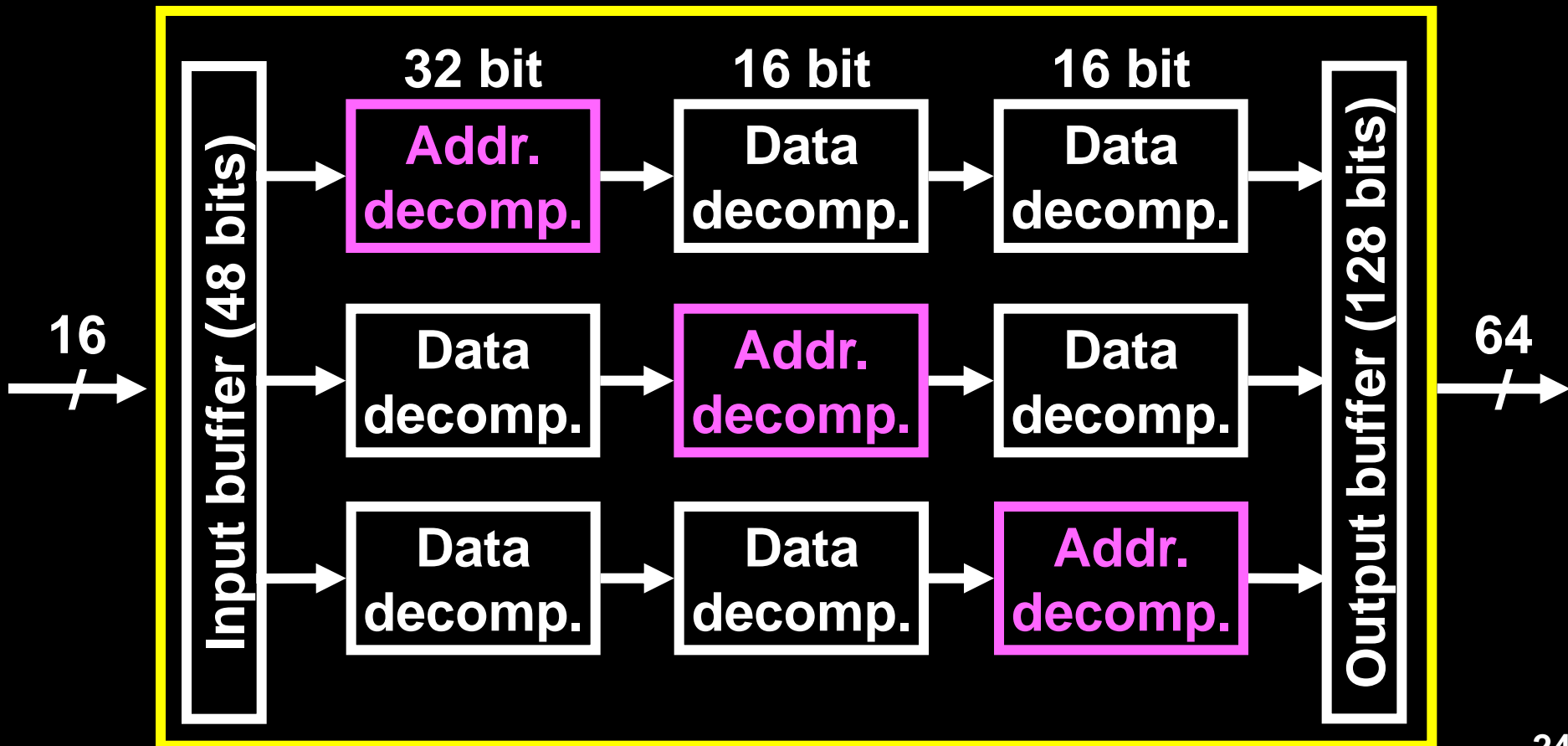
Address/data rule automation

Outline

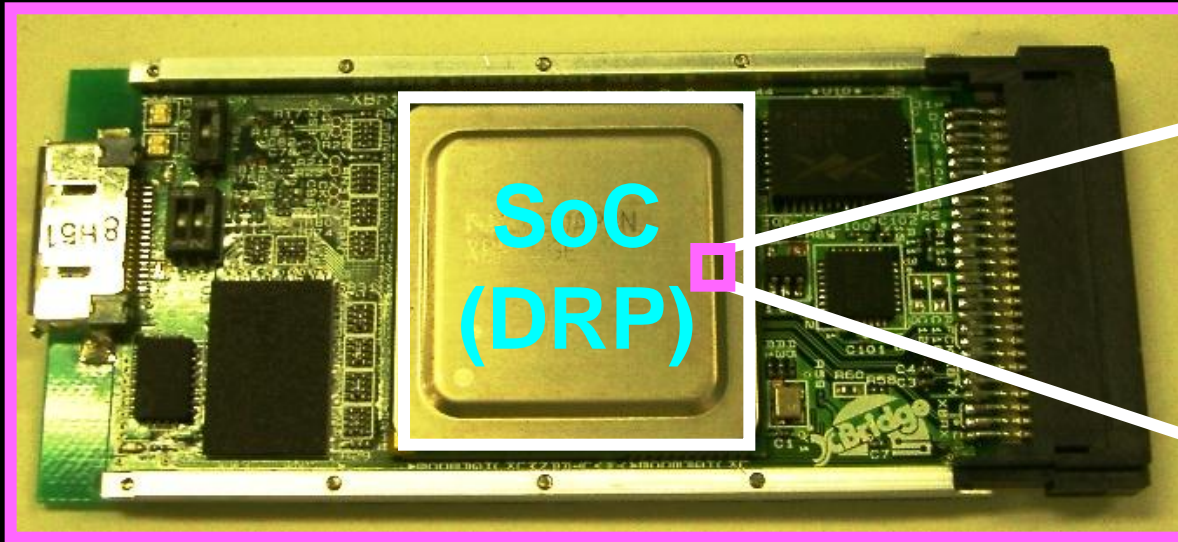
- ✓ • **Background**
- ✓ • **Our solution: DPC**
- ➔ • **Evaluation**
- **Conclusion**

Decompressor Circuit Design

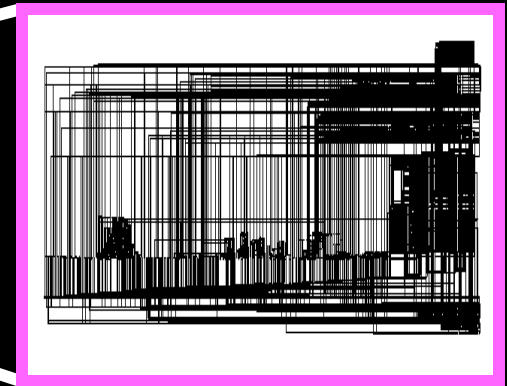
Three sets of sub-decompressors,
decompressing symbols in any order
(speed-optimized design)



Circuit Specifications



Schematic



| | |
|----------------------------|---|
| Process | 40nm |
| Max clock frequency | 200MHz |
| Decomp. bandwidth | 1.6GB/s |
| Power dissipation | 1.8mW (active) / 19.4 μW (idle) |
| Area | 0.046 mm² |

Evaluation Items

Focus

- **Test compression ratio**
- **Test time reduction**
- **Application compression**
(See our paper)

Evaluation Conditions

Test configurations:

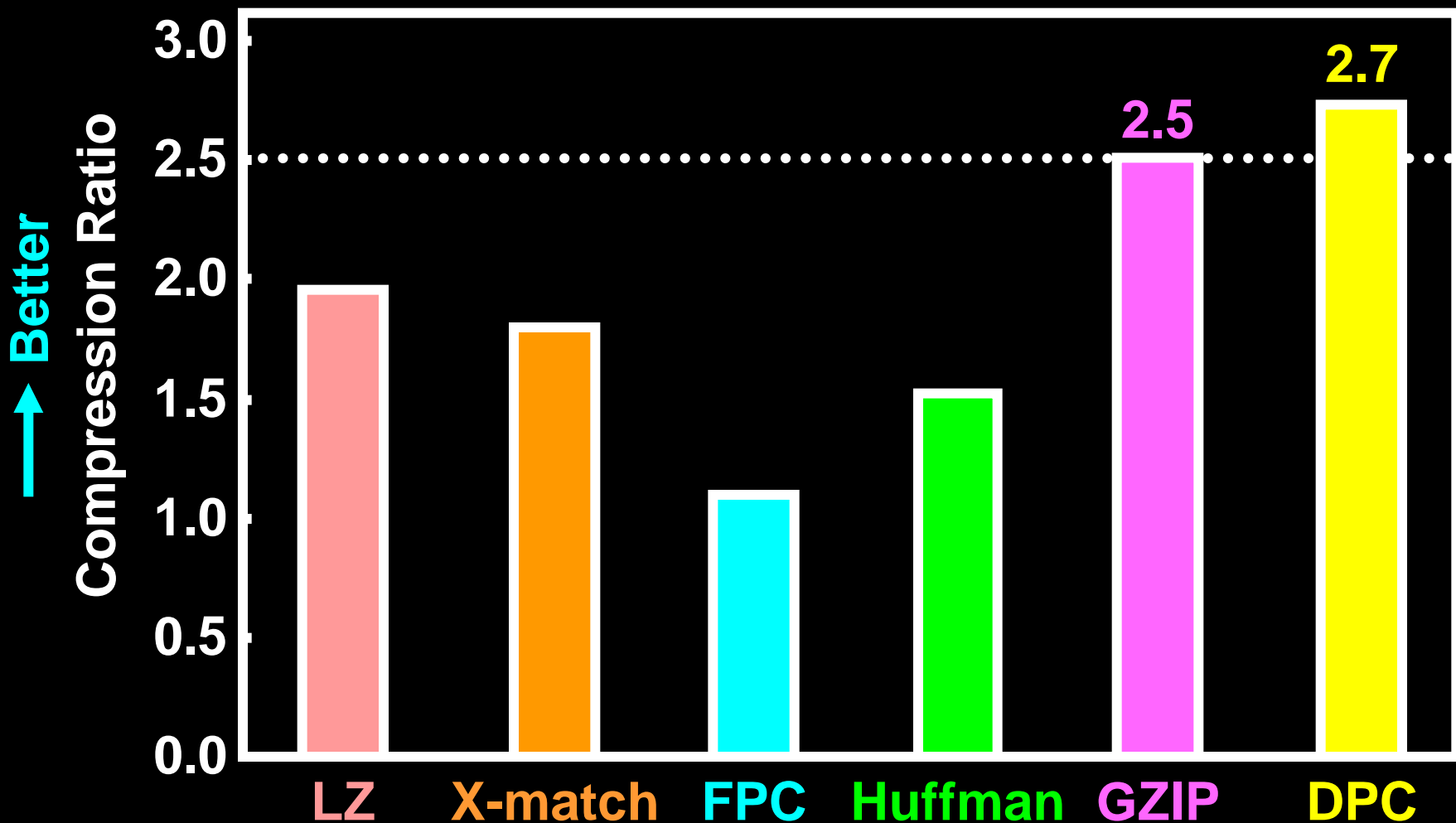
- **Size:** 100s of mega-bits
- **Fault model:** stuck-at, transition, etc.
- **Fault coverage:** product-level

Five compared techniques:

- LZ (dictionary-based)
- X-match (dictionary-based; HW-friendly)
- FPC (rule-based for CPU memory)
- Huffman (coding)
- GZIP (LZ and Huffman)

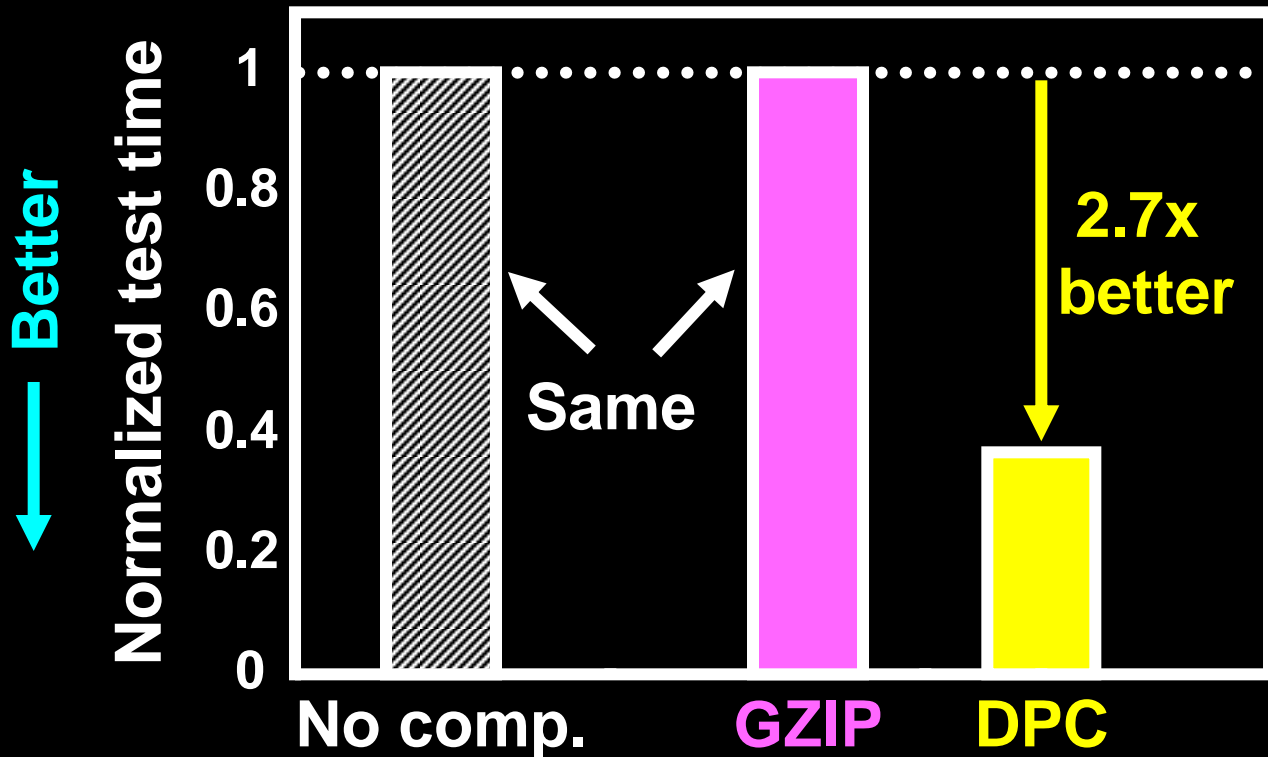
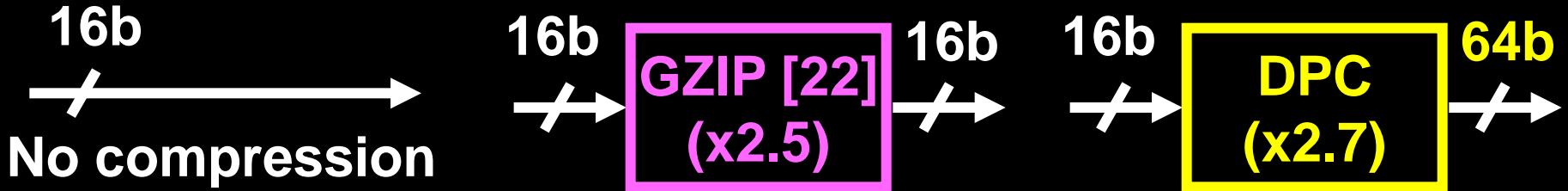
Test Compression Ratio

2.7x better for original test configurations
(slightly better than GZIP)



Test Time Reduction

DPC achieves 2.7x smaller test time



Outline

✓ • **Background**

✓ • **Our solution: DPC**

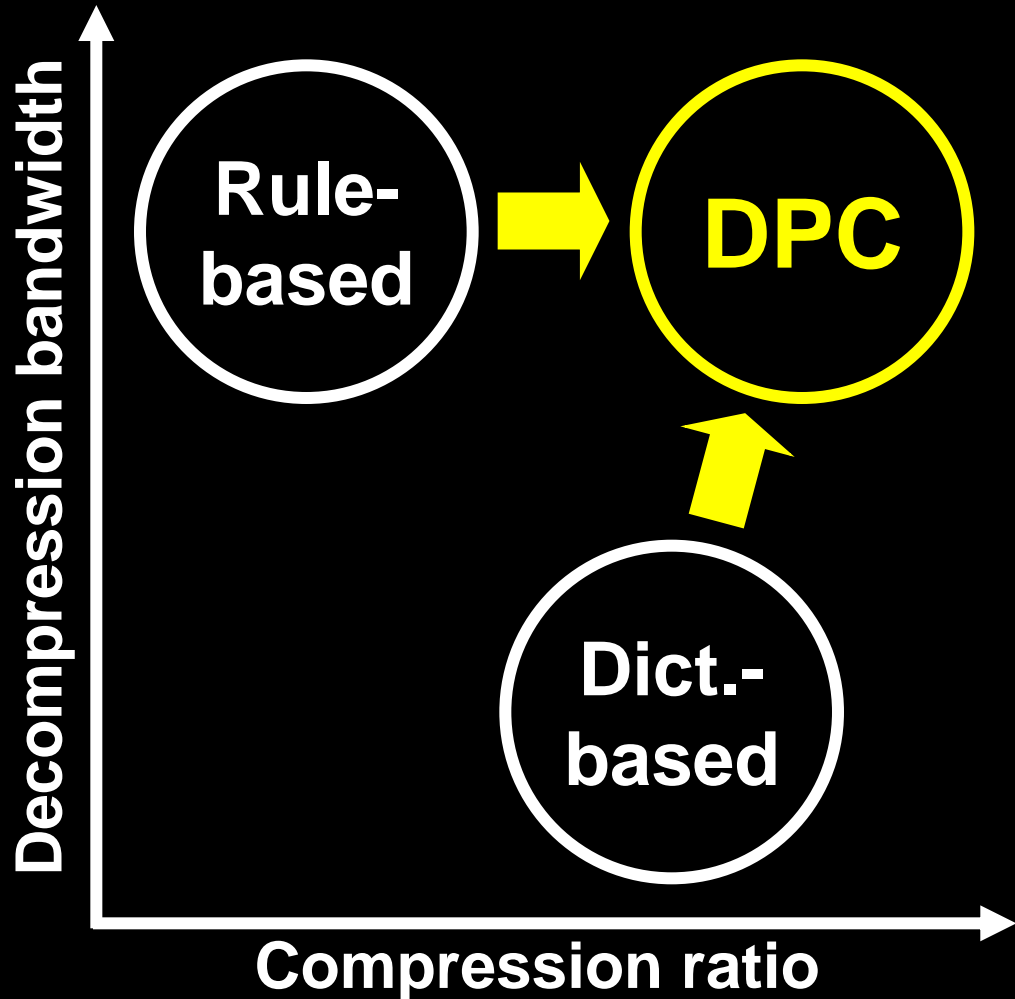
✓ • **Evaluation**

➔ • **Conclusion**

Conclusion

The world's first test compression for DRPs

- High comp. ratio: better than GZIP
- High decompression bandwidth: 16b to 64b
- 2.7x shorter test times



Frequently Asked Questions

- Do you need to modify the compression rules every time test configurations are updated?
 - **Practically, never after the early-design stage.**
- Why can the compression rules be used for application configurations?
 - **Rule automation extracts architecture features**
- Is this approach also effective for other DRP architectures?
 - **I guess so. Any collaboration is welcome.**